DOCUMENT CHANGE REQUEST

DCR number 1144	Changes required for: General		Originator: Steve Jeffery
Date: 2018/04/18	Date sent: 2018/02/08		Organisation: ESCC Executive
Status: IMPLEMENTED			

Title:	Diodes, Silicon, Power Recitifier , High Efficiency, Fast Recovery, based on type BYW81-200		
Number:	5103/029	Issue:	10

Other documents affected:

5103/030-7, 5103/031-8, 5106/016-8, 5106/018-6, 5106/019-7, 5203/010-7, 5204/002-7, 5205/021-7, 5205/022-6, 5205/025-6, 5205/029-4

Page:

Various (as applicable for each ESCC Detail Specification)

Paragraph:

A new paragraph is to be added immediately after the MARKING paragraph, with re-numbering of the subsequent paragraphs of Section 2 as necessary.

Original wording:

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Proposed wording:

A new paragraph titled CASE ISOLATION, with the following wording, shall be added to each Detail Specification:

Case Isolation shall be performed as specified in the ESCC Generic Specification and as follows:
- Test Conditions:
  - o Test voltage: 500Vdc
  - o Duration of application of test voltage: 1s
  - o Points of application of test voltage: between case metal tab and all terminals connected together.
  - o Maximum leakage current: 10nA

Note: for 5103/029, 5106/####, 5203/010 and 5204/002, text defining the applicable Variants shall also be added to the first sentence, e.g. for 5106/018 For Variant 01, Case Isolation shall be performed...

Justification:

This DCR is raised as identified and requested by the ESA QPL-listed manufacturer STMicroelectronics.

The Case Isolation Screening test which has recently been added to ESCC Generic Specification No. 5000 (Para. 8.13; Chart F3A) is applicable to, and shall therefore be performed on, all components in cases TO-254, TO-254AA, TO-257 and TO- 257AA.

Accordingly, a Case Isolation test requirements paragraph is added to each of the ESCC Detail Specifications listed above.

Attachments:
N/A
Modifications:
N/A
Approval signature:
Date signed:
2018-04-18